

CD4051B-Q1 具有逻辑电平转换功能的汽车类 CMOS 单路 8 通道模拟多路复用器或多路信号分离器

1 特性

- 符合面向汽车应用的 AEC-Q100 标准：
 - 温度等级 1：-45°C 至 +125°C， T_A
- 各种数字和模拟信号电平：
 - 数字：3V 至 20V
 - 模拟： $\leq 20V_{P-P}$
- 单电源范围：3V 至 20V ($V_{DD} < 3V$ 时，性能会下降)
- 双电源范围： $\pm 3V$ 至 $\pm 10V$
- 在 $V_{DD} = 15V$ 时，输入范围内的低导通电阻为 125Ω (典型值)
- 在 $V_{DD} = 15V$ 时，低通道漏电流为 $\pm 10pA$ (典型值)
- 低静态功耗： $0.2\mu W$ (典型值)
- 双向信号路径
- ESD 保护 HBM：3000V，CDM：2000V
- 与业界通用的 4051 引脚兼容

2 应用

- 模拟和数字多路复用和多路信号分离
- 模数和数模转换
- 信号门控
- 工厂自动化
- 电视
- 电器
- 消费类音频
- 可编程逻辑电路
- 传感器

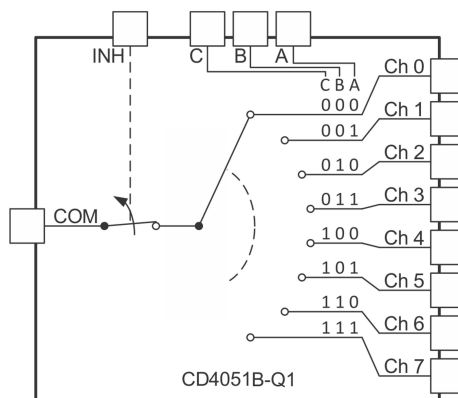
3 说明

CD4051B-Q1 模拟多路复用器和多路信号分离器是数字控制的模拟开关，具有低接通阻抗和极低的关断漏电流。这些多路复用器电路在整个 $V_{DD} - V_{SS}$ 和 $V_{DD} - V_{EE}$ 电源电压范围内，消耗的静态功率极低，而不受控制信号的逻辑状态影响。

封装信息

器件型号	封装 ⁽¹⁾	封装尺寸 ⁽²⁾
CD4051B-Q1	D (SOIC, 16)	9.9mm × 6mm
	PW (TSSOP, 16)	5mm × 6.4mm

- 如需了解所有可用封装，请参阅数据表末尾的可订购产品附录。
- 封装尺寸 (长 × 宽) 为标称值，并包括引脚 (如适用)。



CD4051B-Q1 的功能图



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4 Pin Configuration and Functions

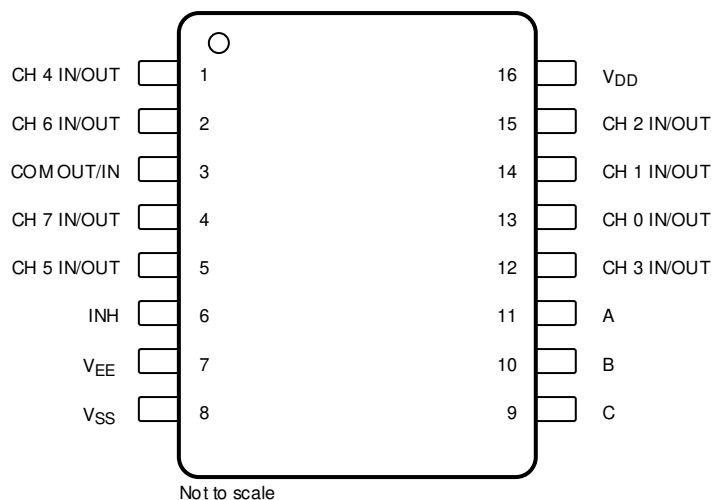


图 4-1. CD4051B-Q1 D or PW Package, (Top View)

表 4-1. Pin Functions CD4051B-Q1

PIN		TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME		
1	CH 4 IN/OUT	I/O	Channel 4 in/out
2	CH 6 IN/OUT	I/O	Channel 6 in/out
3	COM OUT/IN	I/O	Common out/in
4	CH 7 IN/OUT	I/O	Channel 7 in/out
5	CH 5 IN/OUT	I/O	Channel 5 in/out
6	INH	I	Disables all channels. See 表 7-1.
7	V _{EE}	—	Negative power input
8	V _{SS}	—	Ground
9	C	I	Channel select C. See 表 7-1.
10	B	I	Channel select B. See 表 7-1.
11	A	I	Channel select A. See 表 7-1.
12	CH 3 IN/OUT	I/O	Channel 3 in/out
13	CH 0 IN/OUT	I/O	Channel 0 in/out
14	CH 1 IN/OUT	I/O	Channel 1 in/out
15	CH 2 IN/OUT	I/O	Channel 2 in/out
16	V _{DD}	—	Positive power input

(1) I = input, O = output

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)^{(1) (2)}

			MIN	MAX	UNIT
	Supply Voltage	V+ to V-, Voltages Referenced to V _{SS} Terminal	- 0.5	20	V
	DC Input Voltage		- 0.5	V _{DD} +0.5	V
	DC Input Current	Any One Input	- 10	10	mA
T _{JMAX1}	Maximum junction temperature, ceramic package			175	°C
T _{JMAX2}	Maximum junction temperature, plastic package			150	°C
T _{stg}	Storage temperature		- 65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to ground, unless otherwise specified.

5.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±3000	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±2000	

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	NOM	MAX	UNIT
Temperature Range	- 55		125	°C

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		CD4051B-Q1		UNIT
		D (SOIC)	PW (TSSOP)	
		16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	86.7	116.5	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	47.3	47.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	45.3	63.0	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	12.1	6.4	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	44.9	62.1	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

5.5 Electrical Characteristics - CD4051B-Q1

Over operating free-air temperature range, $V_{\text{SUPPLY}} = \pm 5 \text{ V}$, and $R_L = 100 \ \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER	TEST CONDITIONS					MIN	TYP	MAX	UNIT
SIGNAL INPUTS (V _{IS}) AND OUTPUTS (V _{OS}) - CD4051B-Q1									
	V _{IS} (V)	V _{EE} (V)	V _{SS} (V)	V _{DD} (V)	TEMP				
Quiescent Device Current, I _{DD} (Max)		0 V	0 V	5 V	- 55°C		60	μA	
					- 40°C		60		
					25°C	17	60		
					85°C		150		
					125°C		150		
		0 V	0 V	10 V	- 55°C		60		
					- 40°C		60		
					25°C	18	60		
					85°C		300		
					125°C		300		
		0 V	0 V	15 V	- 55°C		60		
					- 40°C		60		
					25°C	18	60		
					85°C		600		
					125°C		600		
		0 V	0 V	20 V	- 55°C		100		
					- 40°C		100		
					25°C	18	100		
					85°C		300 0		
					125°C		300 0		
Drain to Source ON Resistance r _{ON} (Max) 0 ≤ V _{IS} ≤ V _{DD}		0 V	0 V	5 V	- 55°C		800	Ω	
					- 40°C		850		
					25°C	470	105 0		
					85°C		120 0		
					125°C		130 0		
		0 V	0 V	10 V	- 55°C		310		
					- 40°C		300		
					25°C	180	400		
					85°C		520		
					125°C		550		
		0 V	0	15 V	- 55°C		200		
					- 40°C		210		
					25°C	125	240		
					85°C		300		
					125°C		300		

5.5 Electrical Characteristics - CD4051B-Q1 (续)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5\text{ V}$, and $R_L = 100\ \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER			TEST CONDITIONS				MIN	TYP	MAX	UNIT	
Change in ON Resistance (Between Any Two Channels), Δ R _{ON}				0 V	0 V	5 V	25°C		15	Ω	
				0 V	0 V	10 V			10		
				0 V	0 V	15 V			5		
OFF Channel Leakage Current: Any Channel OFF (Max) or ALL Channels OFF (COMMON OUT/IN) (Max)				0 V	0 V	18 V	- 55°C		± 100	nA	
							- 40°C				
							25°C		± 0.01 100 (2)		
							85°C		± 100 0(2)		
							125°C				
ON Channel Leakage Current: Any Channel ON (Max) or ALL Channels ON (COMMON OUT/IN) (Max)			5 or 0	- 5 V	0 V	10.5 V	85°C		± 300	nA	
			5	0 V	0 V	18 V	85°C		± 300		
Capacitance	Input, C _{IS}			0 V	0 V	10 V	25°C		5	pF	
	Output, C _{OS}							CD4051-Q1			30
	Feed through, C _{IOS}										0.2
Prop Delay			V _{DD}	R _L = 200 kΩ		5 V	25°C		30 60	ns	
				C _L = 50 pF		10 V			15 30		
				t _r , t _f = 20 ns		15 V			10 20		

5.5 Electrical Characteristics - CD4051B-Q1 (续)

Over operating free-air temperature range, $V_{\text{SUPPLY}} = \pm 5 \text{ V}$, and $R_L = 100 \ \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS					MIN	TYP	MAX	UNIT
CONTROL (ADDRESS OR INHIBIT), V _C - CD4051B-Q1										
Input Low Voltage, V _{IL} , (Max)					5 V	- 55°C	0.8		V	
						- 40°C	0.8			
						25°C	0.8			
						85°C	0.8			
						125°C	0.8			
					10 V	- 55°C	0.8			
						- 40°C	0.8			
						25°C	0.8			
						85°C	0.8			
						125°C	0.8			
					15 V	- 55°C	0.8			
						- 40°C	0.8			
						25°C	0.8			
						85°C	0.8			
						125°C	0.8			
Input High Voltage, V _{IH} , (Min)					5 V	- 55°C	3.5		V	
						- 40°C	3.5			
						25°C	3.5			
						85°C	3.5			
						125°C	3.5			
					10 V	- 55°C	7			
						- 40°C	7			
						25°C	7			
						85°C	7			
						125°C	7			
					15 V	- 55°C	11			
						- 40°C	11			
						25°C	11			
						85°C	11			
						125°C	11			
Input current, I _{IN} (Max)					18 V	- 55°C	±1		μA	
						- 40°C	±1			
						25°C	±0.6			
						85°C	±1			
						125°C	±1			
Prop agati on Delay Time	Address-to-Signal OUT (Channels ON or OFF) (See Figure 10, Figure 11, and Figure 15)	t _r , t _f = 20ns, C _L = 50 pF, R _L = 10 k Ω	0 V	0 V	5 V		450	720	ns	
			0 V	0 V	10 V		160	320		
			0 V	0 V	15 V		120	240		
			- 5 V	0 V	5 V		225	450		

5.5 Electrical Characteristics - CD4051B-Q1 (续)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5\text{ V}$, and $R_L = 100\ \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS					MIN	TYP	MAX	UNIT
Propagation Delay Time	Inhibit-to-Signal OUT (Channel Turning ON) (See Figure 11)	$t_r, t_f = 20\text{ ns}$, $C_L = 50\text{ pF}$, $R_L = 1\text{ k}\Omega$	0 V	0 V	5 V		400	720	ns	
			0 V	0 V	10 V		160	320		
			0 V	0 V	15 V		120	240		
			- 10 V	0 V	5 V		200	400		
Propagation Delay Time	Inhibit-to-Signal OUT (Channel Turning OFF) (See Figure 17)	$t_r, t_f = 20\text{ ns}$, $C_L = 50\text{ pF}$, $R_L = 10\text{ k}\Omega$	0 V	0 V	5 V		200	450	ns	
			0 V	0 V	10 V		90	210		
			0 V	0 V	15 V		70	160		
			- 10 V	0 V	5 V		130	300		
Input Capacitance, C_{IN} (Any Address or Inhibit Input)			- 5 V	0 V	5 V	25°C	5	7.5	pF	

(1) Peak-to-Peak voltage symmetrical about $(V_{DD} - V_{EE}) / 2$.

(2) Determined by minimum feasible leakage measurement for automatic testing.

5.6 AC Performance Characteristics - CD4051B-Q1

 $V_{DD} = +15\text{ V}$, $V_{SS} = V_{EE} = 0\text{ V}$,

 $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS					TYP	UNIT
	V_{IS} (V)	V_{DD} (V)	R_L (k Ω)				
Cutoff (- 3dB) Frequency Channel ON (Sine Wave Input)	5 ⁽¹⁾	10	1	V_{OS} at Common OUT/IN	CD4051-Q1	20	MHz
	$V_{EE} = V_{SS}$, $20\text{Log}(V_{OS}/V_{IS}) = -3\text{ dB}$			V_{OS} at Any Channel		60	
Total Harmonic Distortion, THD	2 ⁽¹⁾	5	10			0.3%	%
	3 ⁽¹⁾	10	10			0.2%	
	5 ⁽¹⁾	15	10			0.12%	
	$V_{EE} = V_{SS}$, $f_{IS} = 1\text{ kHz}$ Sine Wave						
- 40dB Feedthrough Frequency (All Channels OFF)	5 ⁽¹⁾	10	1	V_{OS} at Common OUT/IN	CD4051-Q1	12	MHz
	$V_{EE} = V_{SS}$, $20\text{Log}(V_{OS}/V_{IS}) = -40\text{ dB}$			V_{OS} at Any Channel		8	MHz
- 40dB Signal Crosstalk Frequency	5 ⁽¹⁾	10	1			3	MHz
Address-or-Inhibit-to- Signal Crosstalk		10	10 ⁽²⁾			65	mV _{PEAK}
	$V_{EE} = 0$, $V_{SS} = 0$, t_r , $t_f = 20\text{ ns}$, mV _{PEAK} $V_{CC} = V_{DD} - V_{SS}$ (Square Wave)					65	mV _{PEAK}

(1) Peak-to-Peak voltage symmetrical about $(V_{DD} - V_{EE}) / 2$.

(2) Both ends of channel.

5.7 Typical Characteristics

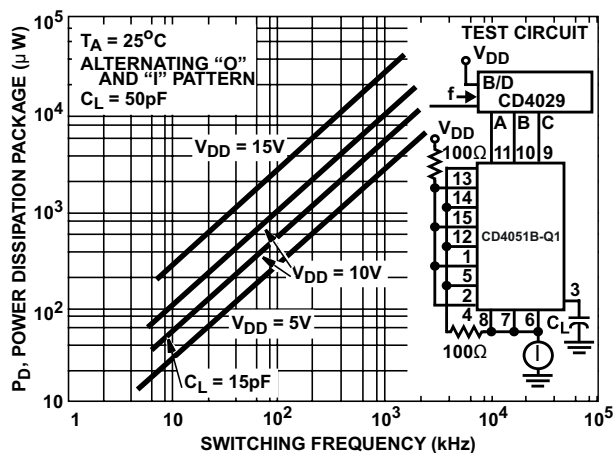


图 5-1. Dynamic Power Dissipation vs Switching Frequency (CD4051B-Q1)

6 Parameter Measurement Information

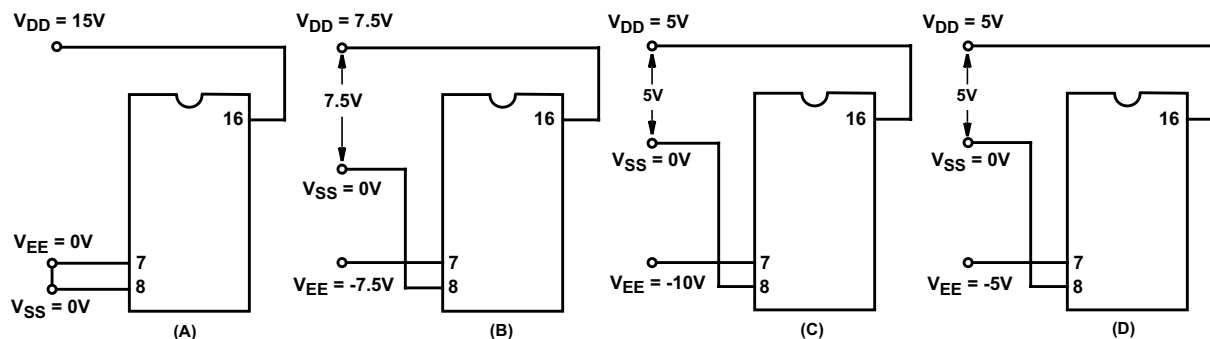


图 6-1. Typical Bias Voltages

备注

The ADDRESS (digital-control inputs) and INHIBIT logic levels are: 0 = V_{SS} and 1 = V_{DD} . The analog signal (through the TG) may swing from V_{EE} to V_{DD} .

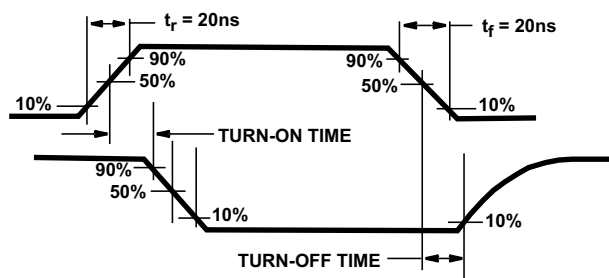


图 6-2. Waveforms, Channel Being Turned ON ($R_L = 1\text{ k}\Omega$)

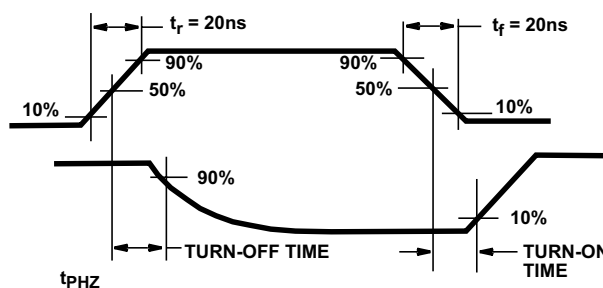


图 6-3. Waveforms, Channel Being Turned OFF ($R_L = 1\text{ k}\Omega$)

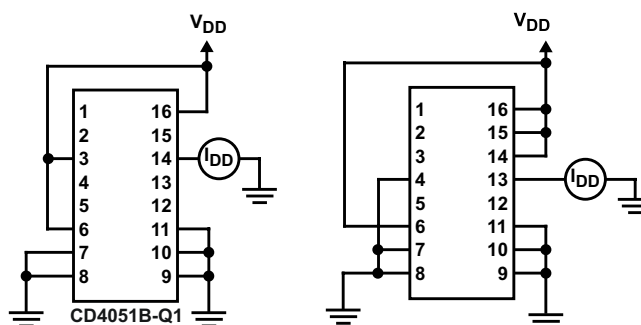


图 6-4. OFF Channel Leakage Current - Any Channel OFF

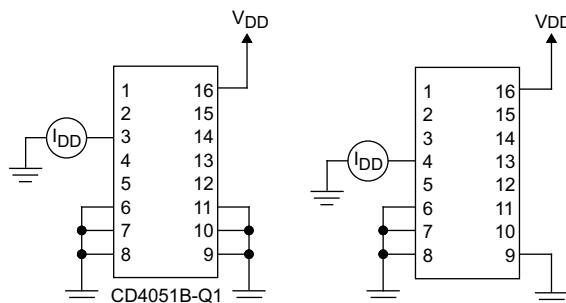


图 6-5. On Channel Leakage Current - Any Channel On

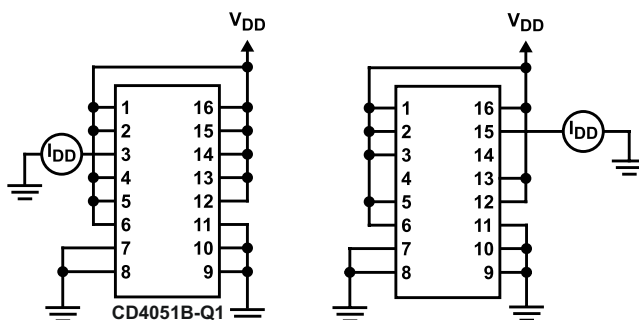


图 6-6. OFF Channel Leakage Current - All Channels OFF

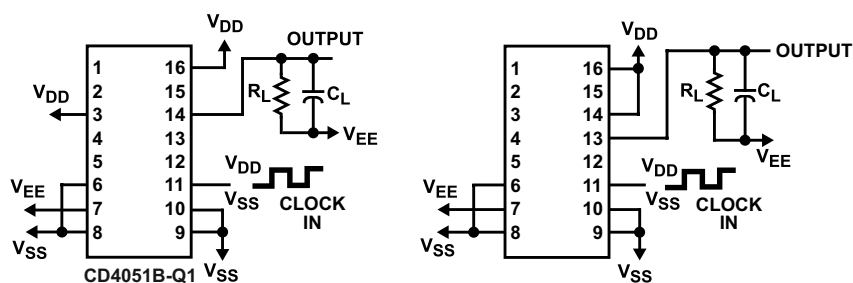


图 6-7. Propagation Delay - Address Input to Signal Output

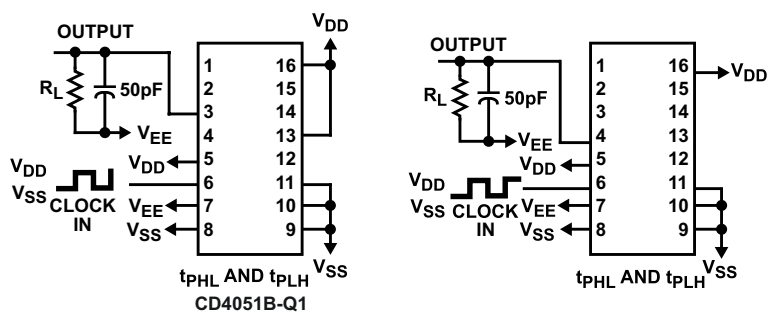
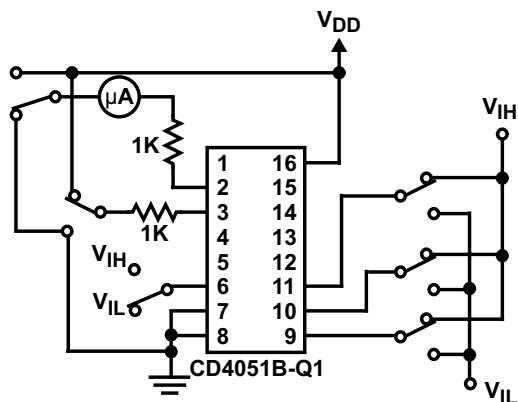
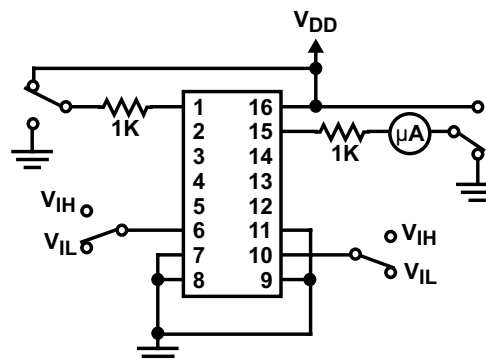


图 6-8. Propagation Delay - Inhibit Input to Signal Output



MEASURE $< 2\mu\text{A}$ ON ALL
"OFF" CHANNELS (e.g., CHANNEL 6)



MEASURE $< 2\mu\text{A}$ ON ALL
"OFF" CHANNELS (e.g., CHANNEL 6)

图 6-9. Input Voltage Test Circuits (Noise Immunity)

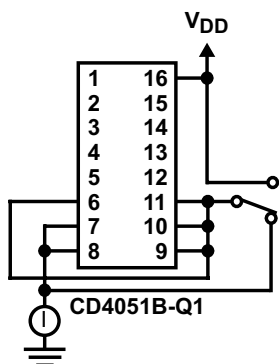


图 6-10. Quiescent Device Current

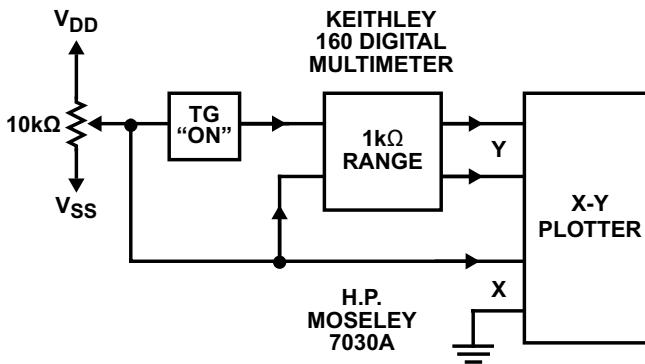
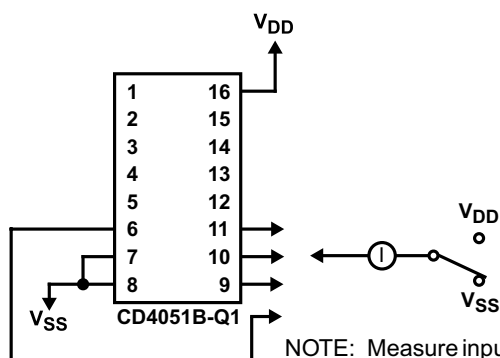


图 6-11. Channel ON Resistance Measurement Circuit



NOTE: Measure inputs sequentially,
to both V_{DD} and V_{SS} connect all
unused inputs to either V_{DD} or V_{SS} .

图 6-12. Input Current

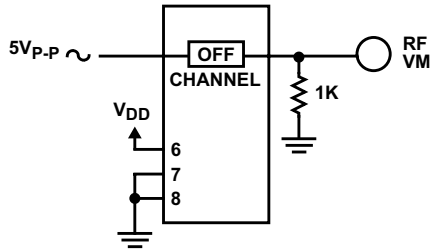


图 6-13. Feed-Through (All Types)

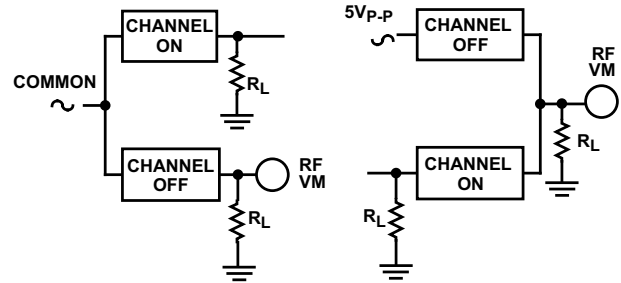


图 6-14. Crosstalk Between Any Two Channels (All Types)

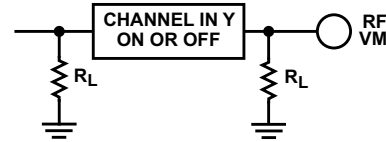
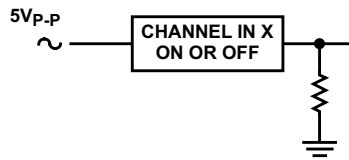


图 6-15. Crosstalk Between Duals or Triplets ()

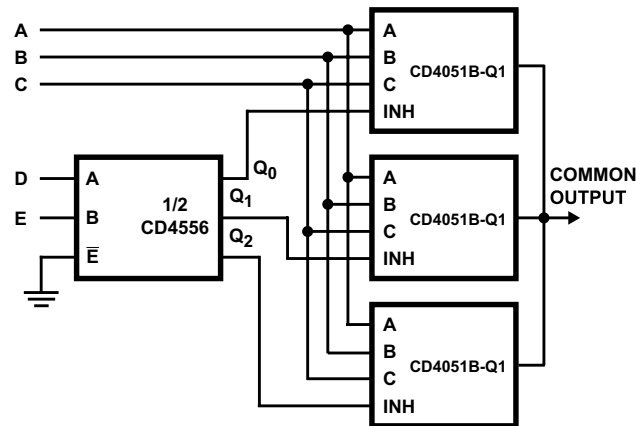


图 6-16. 24-to-1 MUX Addressing

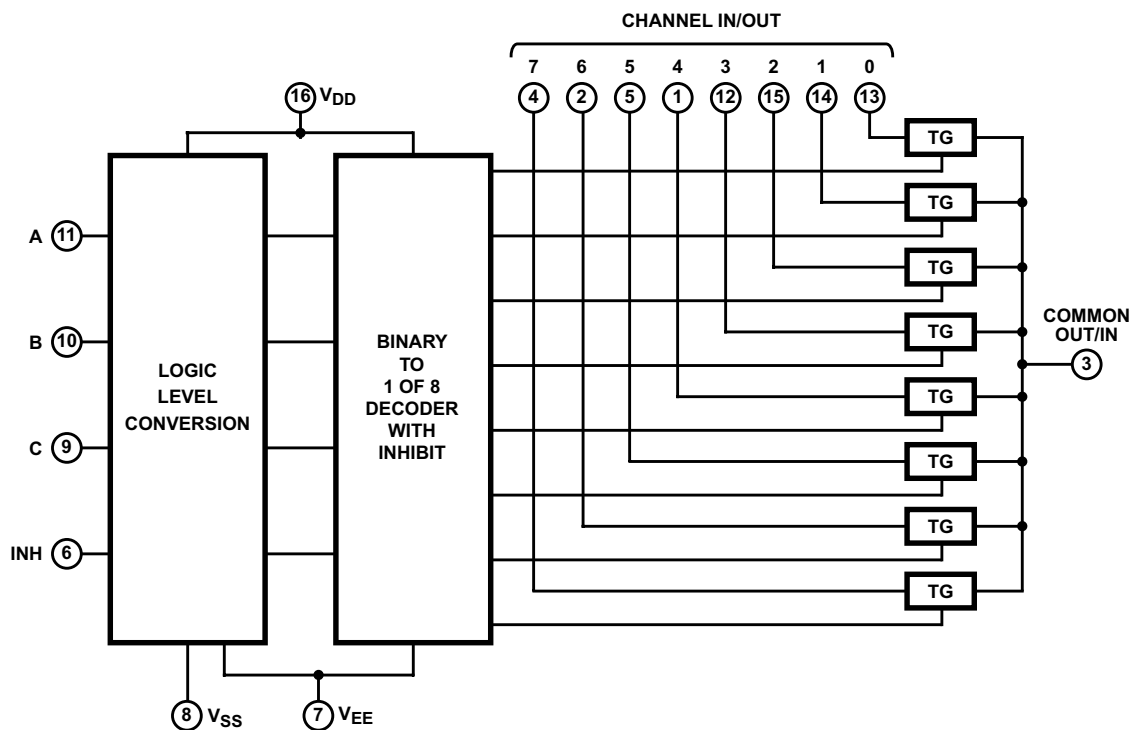
7 Detailed Description

7.1 Overview

The CD4051B-Q1 device is a single 8-channel multiplexer having three binary control inputs, A, B, and C, and an inhibit input. The three binary signals select 1 of 8 channels to be turned on, and connect one of the 8 inputs to the output.

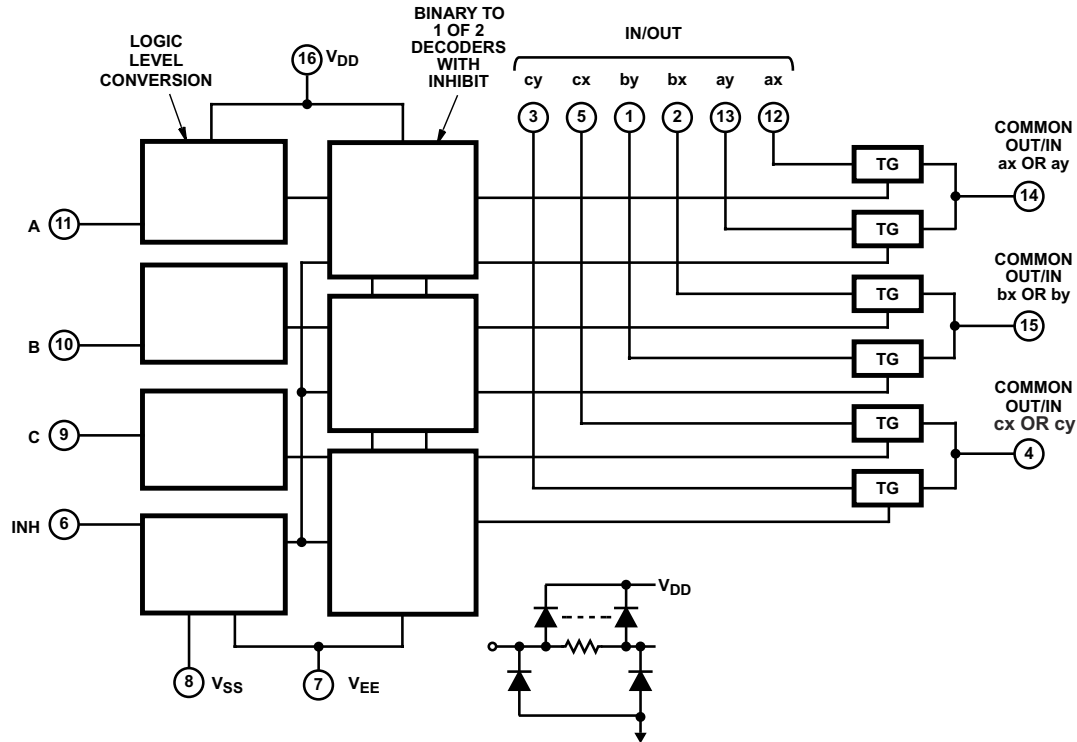
When these devices are used as demultiplexers, the CHANNEL IN/OUT terminals are the outputs and the COMMON OUT/IN terminals are the inputs.

7.2 Functional Block Diagrams



All inputs are protected by standard CMOS protection network.

图 7-1. Functional Block Diagram, CD4051B-Q1



All inputs are protected by standard CMOS protection network.

图 7-2. Functional Block Diagram,

7.3 Feature Description

The CD4051B-Q1 line of multiplexers and demultiplexers can accept a wide range of digital and analog signal levels. Digital signals range from 3V to 20V, and analog signals are accepted at levels $\leq 20V$. The devices have low ON resistance, typically 125Ω over $15V_{P-P}$ signal input range for $V_{DD} - V_{EE} = 18V$. This feature allows for very little signal loss through the switch.

The CD4051B-Q1 devices also have high OFF resistance, which keeps from the devices from wasting power when the switch is in the OFF position, with typical channel leakage of $\pm 100pA$ at $V_{DD} - V_{EE} = 18V$.

Binary address decoding on the chip makes channel selection simple. When channels are changed, a break-before-make system eliminates channel overlap.

7.4 Device Functional Modes

表 7-1. Truth Table

INPUT STATES				ON CHANNEL(S)
INHIBIT	C	B	A	
CD4051B-Q1				
L	L	L	L	0
L	L	L	H	1
L	L	H	L	2
L	L	H	H	3
L	H	L	L	4
L	H	L	H	5
L	H	H	L	6
L	H	H	H	7

表 7-1. Truth Table (续)

INPUT STATES				ON CHANNEL(S)
INHIBIT	C	B	A	
H	X	X	X	None

8 Application and Implementation

备注

以下应用部分中的信息不属于 TI 器件规格的范围，TI 不担保其准确性和完整性。TI 的客户应负责确定器件是否适用于其应用。客户应验证并测试其设计，以确保系统功能。

8.1 Application Information

The CD4051B-Q1 multiplexers and demultiplexers can be used for a wide variety of applications.

8.2 Typical Application

One application of the CD4051B-Q1 is to use it in conjunction with a microcontroller to poll a keypad. 图 8-1 shows the basic schematic for such a polling system. The microcontroller uses the channel select pins to cycle through the different channels while reading the input to see if a user is pressing any of the keys. This application is a very robust setup, allowing for multiple simultaneous key-presses with very little power consumption. This setup also uses very few pins on the microcontroller. The down side of polling is that the microcontroller must continually scan the keys for a press and can do little else during this process.

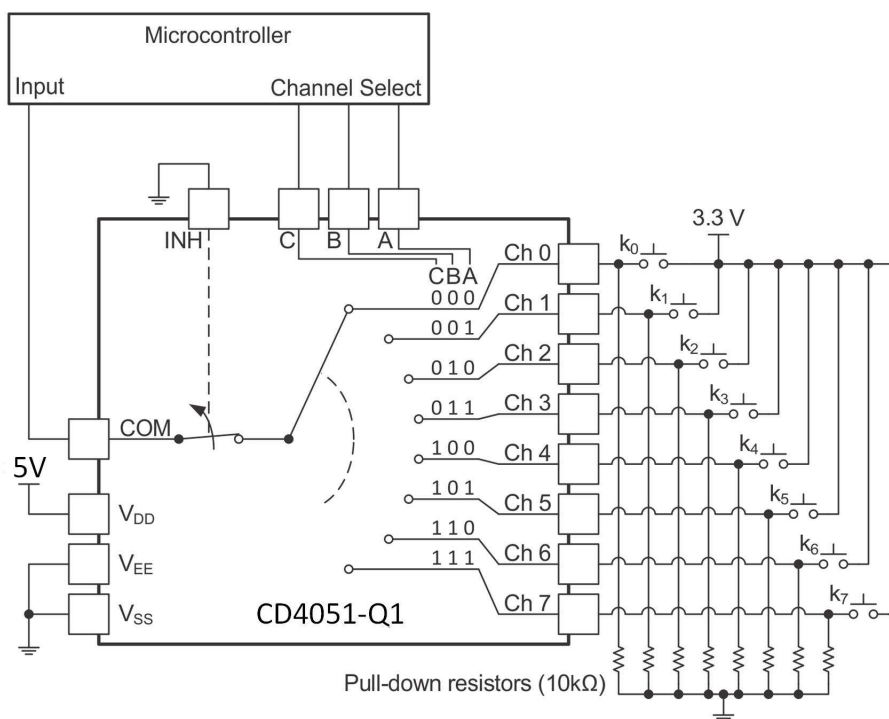


图 8-1. The CD4051B-Q1 Being Used to Help Read Button Presses on a Keypad

8.2.1 Design Requirements

These devices use CMOS technology and have balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads, so routing and load conditions should be considered to prevent ringing.

8.2.2 Detailed Design Procedure

1. Recommended Input Conditions:

- For switch time specifications, see propagation delay times in 节 5.5.
- Inputs should not be pushed more than 0.5V above V_{DD} or below V_{EE} .
- For input voltage level specifications for control inputs, see V_{IH} and V_{IL} in 节 5.5.

2. Recommended Output Conditions:

- Outputs should not be pulled above V_{DD} or below V_{EE} .

3. Input or output current consideration:

- The CD4051B-Q1 series of parts do not have internal current drive circuitry and thus cannot sink or source current. Any current will be passed through the device.

8.2.3 Application Curve

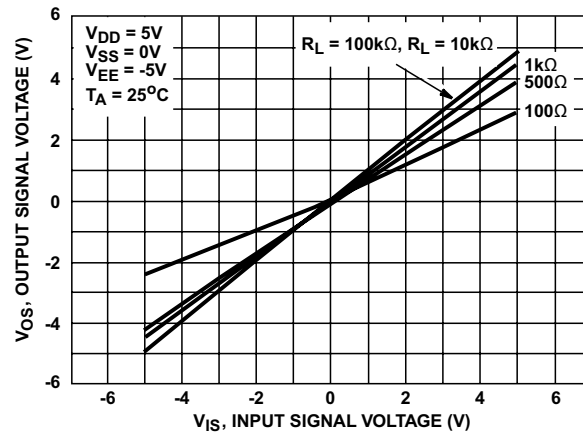


图 8-2. ON Characteristics for 1 of 8 Channels (CD4051B-Q1)

8.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the [节 5.5](#).

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a $0.1 \mu F$ bypass capacitor is recommended. If there are multiple pins labeled V_{CC} , then a $0.01 \mu F$ or $0.022 \mu F$ capacitor is recommended for each V_{CC} because the V_{CC} pins will be tied together internally. For devices with dual supply pins operating at different voltages, for example V_{CC} and V_{DD} , a $0.1 \mu F$ bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. $0.1 \mu F$ and $1 \mu F$ capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

8.4 Layout

8.4.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This reflection is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self-inductance of the trace — resulting in the reflection. It is a given that not all PCB traces can be straight, and so they will have to turn corners. 图 8-3 shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.

8.4.2 Layout Example

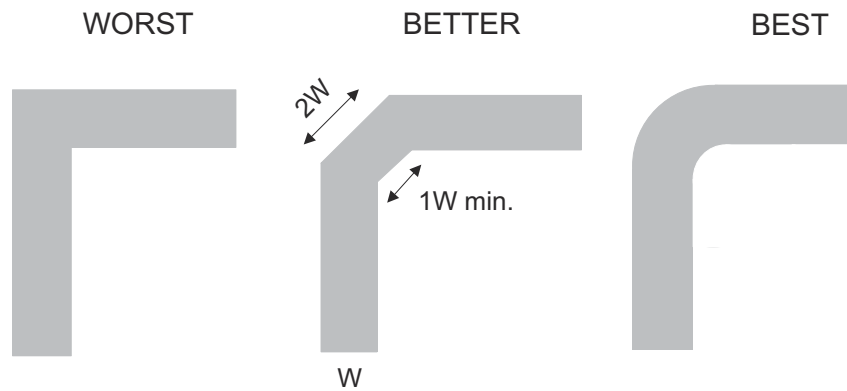


图 8-3. Trace Example

9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, [Implications of Slow or Floating CMOS Inputs](#)

9.2 接收文档更新通知

要接收文档更新通知，请导航至 [ti.com](#) 上的器件产品文件夹。点击 [通知](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

9.3 支持资源

[TI E2E™ 中文支持论坛](#) 是工程师的重要参考资料，可直接从专家处获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题，获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [使用条款](#)。

9.4 Trademarks

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9.5 静电放电警告



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ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

9.6 术语表

TI 术语表

本术语表列出并解释了术语、首字母缩略词和定义。

10 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision C (March 2023) to Revision D (March 2025)	Page
• 更新了 节 1	1
• 将 CD4053B-Q1 移到了 SCHS469.....	1
• Updated HBM & CDM ESD values.....	4
• Updated Figure 8-1 to 5V VDD.....	19

Changes from Revision B (April 2019) to Revision C (March 2023)	Page
• 更新了整个文档中的表格、图和交叉参考的编号格式.....	1
• 更新了整个数据表中的 CD4051-Q1 规格.....	1

Changes from Revision A (January 2008) to Revision B (April 2019)	Page
• 添加了引脚配置和功能部分、ESD 等级表、特性说明部分、器件功能模式、应用和实施部分、电源相关建议部分、布局部分、器件和文档支持部分，以及机械、封装和可订购信息部分.....	1
• 从数据表中删除了器件型号 CD4052B-Q1.....	1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
CD4051BQPWRG4Q1	Obsolete	Production	TSSOP (PW) 16	-	-	Call TI	Call TI	-40 to 125	CM051BQ
CD4051BQPWRQ1	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CM051BQ
CD4051BQPWRQ1.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CM051BQ

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

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OTHER QUALIFIED VERSIONS OF CD4051B-Q1 :

- Catalog : [CD4051B](#)

- Military : [CD4051B-MIL](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION



*All dimensions are nominal

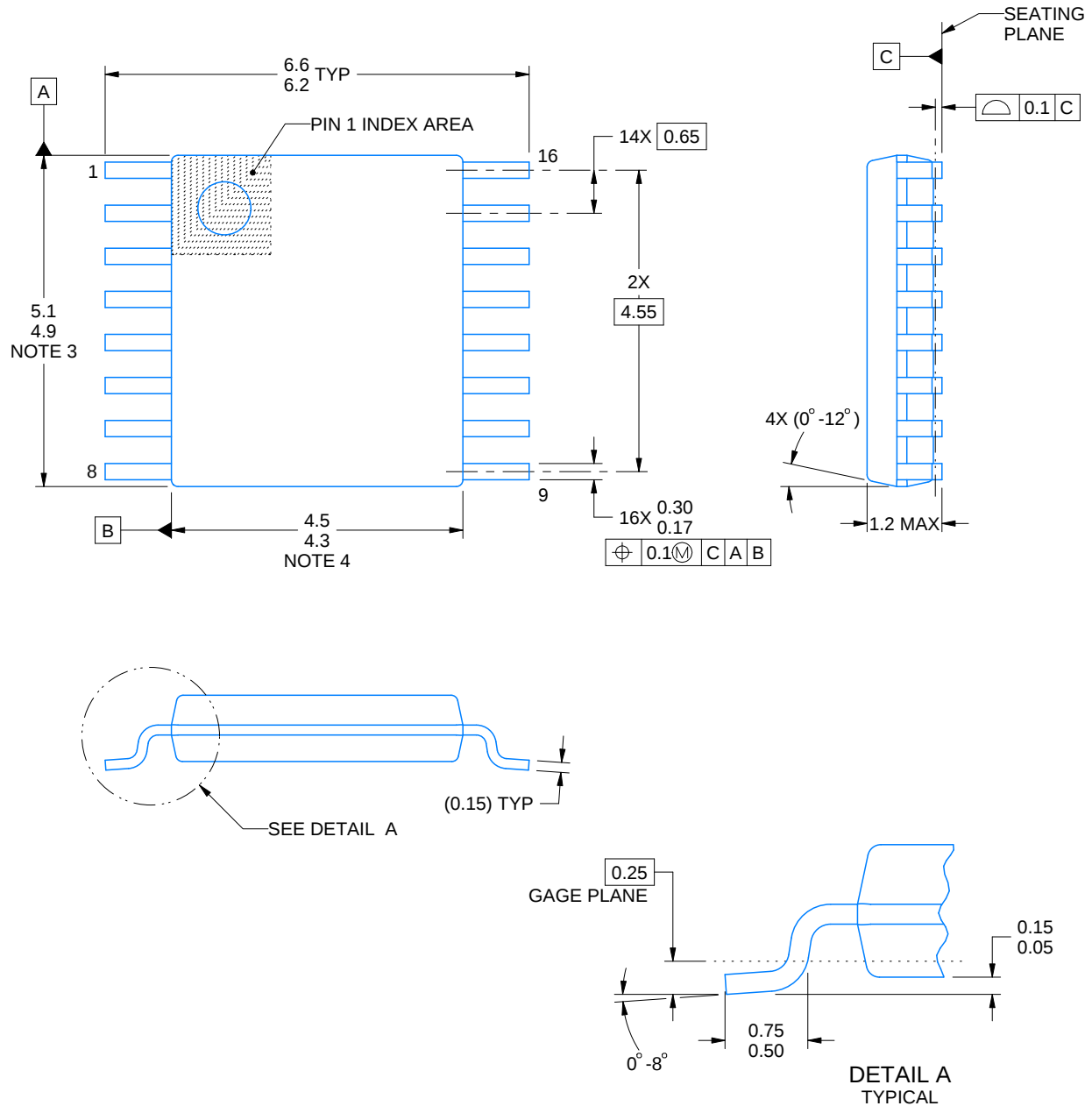
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4051BQPWRQ1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD4051BQPWRQ1	TSSOP	PW	16	2000	353.0	353.0	32.0



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NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

EXAMPLE STENCIL DESIGN

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220204/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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